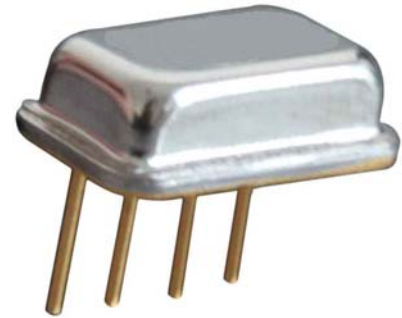


Application

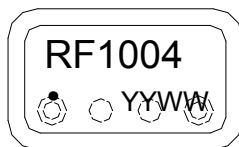
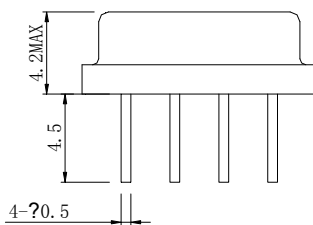
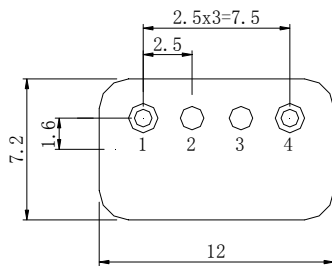
- Low-loss SAW component
- Low amplitude ripple
- Sharp rejections at both out-bands
- Usable passband 300.0 KHZ

Features

- RoHS compatible
- Package size 12.0x7.20x4.20mm³
- Package Code SC04-01
- Electrostatic Sensitive Device(ESD)



Package Dimensions (SC04-01)



Pin Configuration

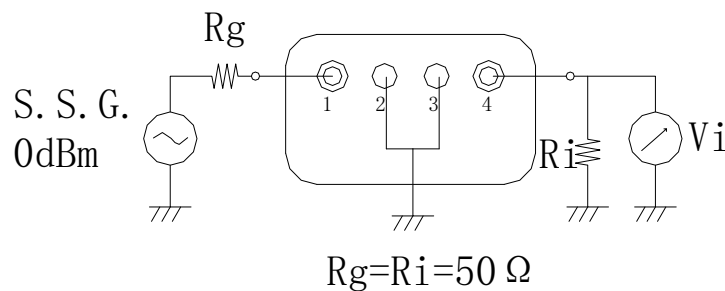
Pin No.	Description
1	Input
4	Output
2,3	Case Ground

Marking Description

RF	R	Trademark & Manufacturer
	F	SAW Filter
1004	Part Number	
●	Pin 1	
YYWW	Year Code & Week Code	

*Fig: If the products produced in 06th week of 2015, The year code & week code is 1506.

Test Circuit (Bottom View)



Performance**Maximum Rating**

Item		Value	Unit
DC Voltage	V_{DC}	3	V
Operation Temperature	T	-40 ~ +85	°C
Storage Temperature	T_{stg}	-55 ~ +125	°C
RF Power Dissipation	P	10	dBm

Electronic Characteristics

Test Temperature: $25^{\circ}\text{C} \pm 2^{\circ}\text{C}$

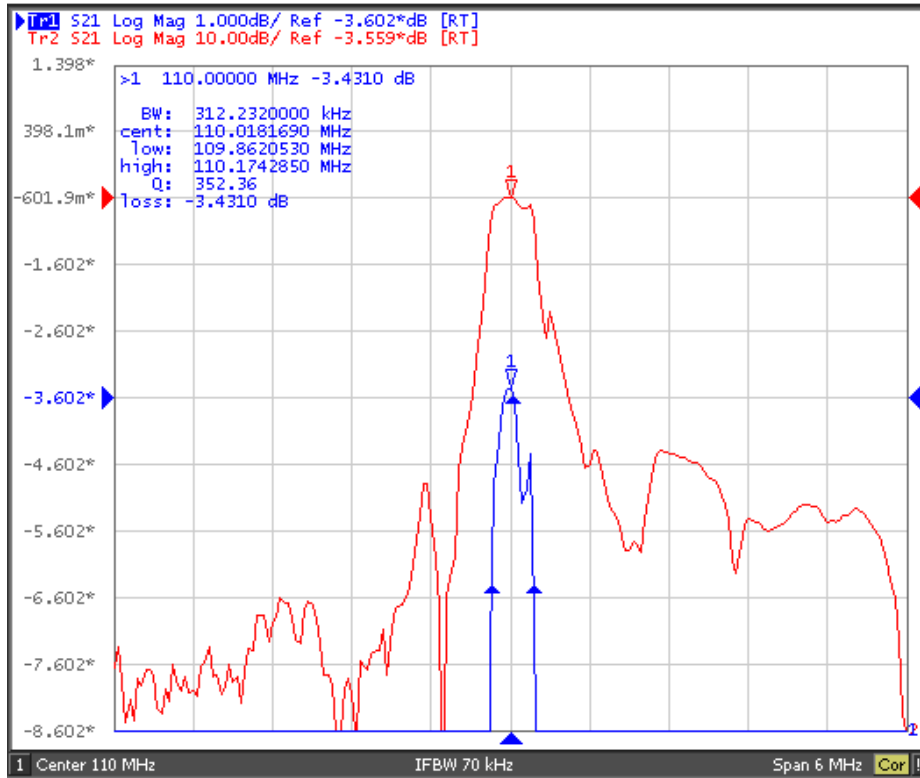
Terminating source impedance: 50Ω

Terminating load impedance: 50Ω

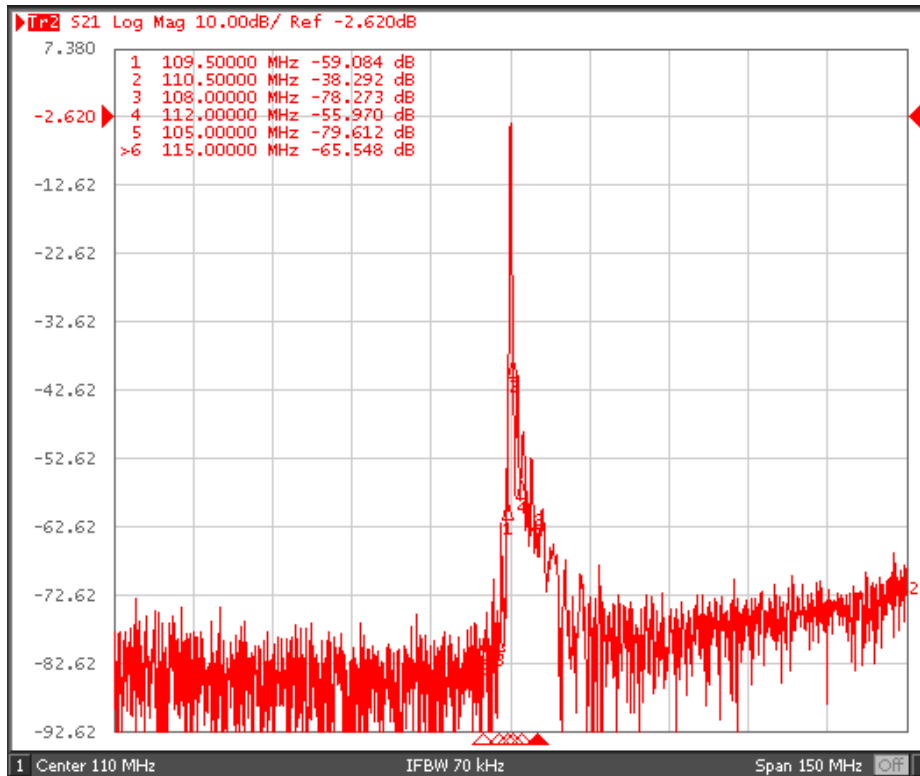
Item		Minimum	Typical	Maximum	Unit
Center Frequency	f_c	109.97	110.00	110.06	MHz
Insertion Loss	IL		3.5	4.5	dB
Amplitude Ripple (p-p)	$\Delta\alpha$		2.0	2.5	dB
3dB Bandwidth	BW_{3dB}	250	310		kHz
Absolute Delay	GDR		3.0	3.5	us
Absolute Attenuation	α				
	$F0 \pm 0.5\text{MHz} - F0 \pm 2\text{MHz}$	30.0	35.0		dB
	$F0 \pm 2\text{MHz} - F0 \pm 75\text{MHz}$	50.0	55.0		dB

Frequency Characteristics

Frequency Response



Frequency Response (wideband)



Notes

1. As a result of the particularity of inner structure of SAW products, it easy to be breakdown by electrostatic, so we should pay attention to **ESD protect** in the test.
2. **Static voltage** between signal load and ground may cause deterioration and destruction of the component. Please avoid static voltage.
3. **Ultrasonic cleaning** may cause deterioration and destruction of the component. Please avoid ultrasonic cleaning.
4. Only leads of component may **be soldered**. Please avoid soldering another part of component.
5. There is a close relationship between the device's performance and **matching network**. The specifications of this device are based on the test circuit shown above. L and C values may change depending on board layout. Values shown are intended as a guide only.